

OptiMOS[™]5 Power-Transistor

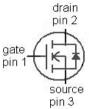
Features

- N-channel, normal level
- Optimized for FOM_{OSS}
- Very low on-resistance R_{DS(on)}
- 175 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC¹⁾ for target application
- Ideal for high-frequency switching and synchronous rectification

Product Summary

$V_{ m DS}$	100	V
R _{DS(on).max}	2.0	mΩ
I _D	176	А





(HAI)	Halo	gen-Free
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Туре	IPB020N10N5
	(i) lestineon
Package	PG-TO263-3
Marking	020N10N5

Maximum ratings, at T_A =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	T _C =25 °C	176	Α
		T _C =100 °C	135	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	704	
Avalanche energy, single pulse	E _{AS}	I_{D} =50 A, R_{GS} =25 Ω	1166	mJ
Gate source voltage	V_{GS}		±20	V
Power dissipation	P_{tot}	T _C =25 °C	375	W
Operating and storage temperature	$T_{\rm j}, T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

¹⁾J-STD20 and JESD22

²⁾ see Diagram 3

1.3

248

124

2

Ω

S



Gate resistance⁵⁾

Transconductance

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R_{thJC}		-	0.3	0.4	K/W
Thermal resistance, junction -	R_{thJA}	minimal footprint	-	-	62	
ambient		6 cm ² cooling area ⁴⁾	-	-	40	
Soldering temperature, wave and reflow soldering are allowed	T_{sold}	reflow MSL1			260	°C
Electrical characteristics, at T_j =25	°C, unless	otherwise specified		!	!	
Static characteristics						
Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =1 mA	100	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 270 \ \mu {\rm A}$	2.2	3	3.8	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =100 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	-	0.1	7	μA
		V _{DS} =100 V, V _{GS} =0 V, T _j =125 °C	-	10	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	1	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =100 A	-	1.7	2.0	mΩ
		V _{GS} =6 V, I _D =50 A	-	2.0	2.5	

I_D=100 A

 $|V_{\rm DS}| > 2|I_{\rm D}|R_{\rm DS(on)max}$

 R_{G}

 g_{fs}

 $^{^{4)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics ⁵⁾						
Input capacitance	Ciss		-	12000	15600	pF
Output capacitance	Coss	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =50 V, f =1 MHz	-	1810	2353	1
Reverse transfer capacitance	C _{rss}		-	80	140	
Turn-on delay time	$t_{d(on)}$		-	33	-	ns
Rise time	t _r	V _{DD} =50 V, V _{GS} =10 V, I _D =100 A,	-	26	-	
Turn-off delay time	$t_{d(off)}$	$R_{G,ext}$ =1.6 Ω	-	77	-	
Fall time	t _f		-	29	-	
Gate Charge Characteristics ⁶⁾				,		T
Gate to source charge	Q _{gs}		-	54	-	nC
Gate to drain charge ⁵⁾	Q_{gd}	<u> </u>	-	34	51	
Switching charge	Q_{sw}	$V_{\rm DD}$ =50 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V	-	52	-	
Gate charge total ⁵⁾	Q_g		-	168	210	
Gate plateau voltage	$V_{\rm plateau}$		-	4.5	ı	V
Output charge ⁵⁾	Q _{oss}	V _{DD} =50 V, V _{GS} =0 V	-	213	283	nC
Reverse Diode						
Diode continous forward current	Is	- T _C =25 °C	-	-	176	Α
Diode pulse current	I _{S,pulse}	7 C=20 C	-	-	480	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =100 A, T _j =25 °C	-	0.9	1.2	V
Reverse recovery time ⁵⁾	t _{rr}	V _R =50 V, I _F =I _S ,	-	99	198	ns
Reverse recovery charge ⁵⁾	Q _{rr}	di _F /dt=100 A/µs	-	287	574	nC

⁵⁾ Defined by design. Not subject to production test⁶⁾ See figure 16 for gate charge parameter definition



1 Power dissipation

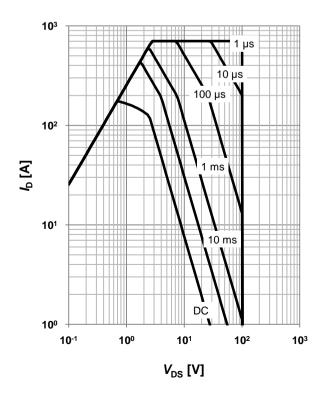
 $P_{\text{tot}} = f(T_{\text{C}})$

400 300 ∑ 200 Q 200 100 0 0 50 100 150 200 *T*_C [°C]

3 Safe operating area

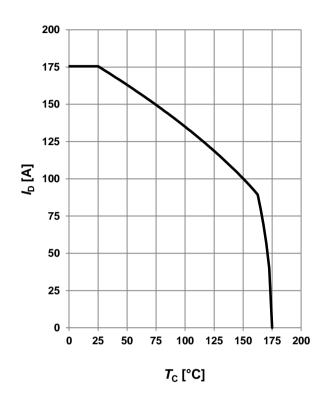
 I_D =f(V_{DS}); T_C =25 °C; D=0

parameter: t_p



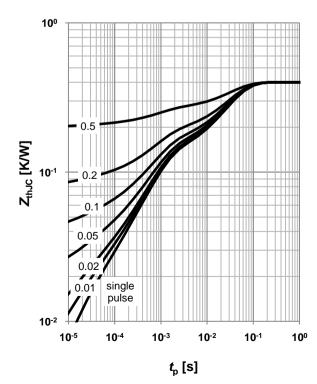
2 Drain current

 $I_{D}=f(T_{C}); V_{GS}\geq 10 \text{ V}$



4 Max. transient thermal impedance

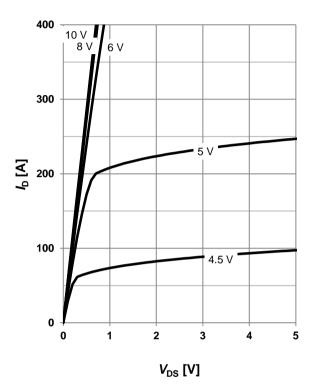
 $Z_{\text{thJC}} = f(t_{\text{p}})$ parameter: $D = t_{\text{p}}/T$





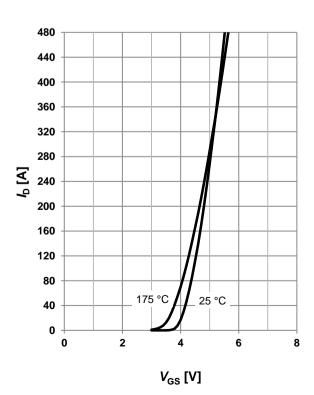
5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 \text{ °C}$ parameter: V_{GS}



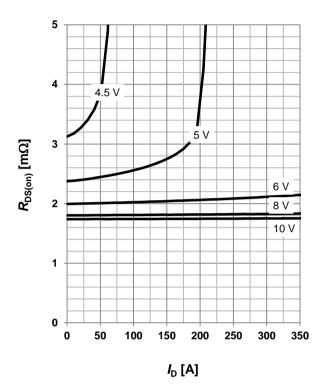
7 Typ. transfer characteristics

 $I_{\rm D} = f(V_{\rm GS}); |V_{\rm DS}| > 2|I_{\rm D}|R_{\rm DS(on)max}$ parameter: $T_{\rm j}$



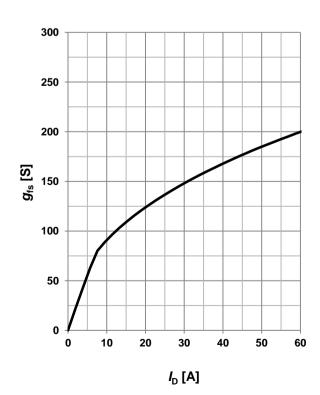
6 Typ. drain-source on resistance

 $R_{\mathrm{DS(on)}}$ =f(I_{D}); T_{j} =25 °C parameter: V_{GS}



8 Typ. forward transconductance

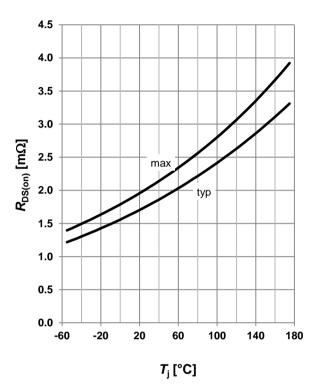
 g_{fs} =f(I_D); T_j =25 °C





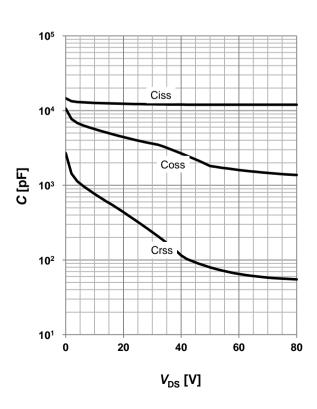
9 Drain-source on-state resistance

 $R_{DS(on)} = f(T_i); I_D = 100 \text{ A}; V_{GS} = 10 \text{ V}$



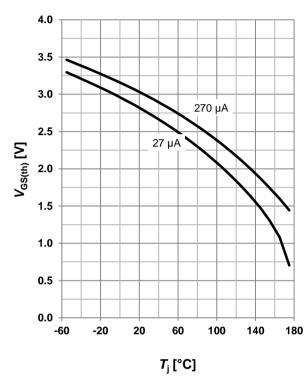
11 Typ. capacitances

 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$



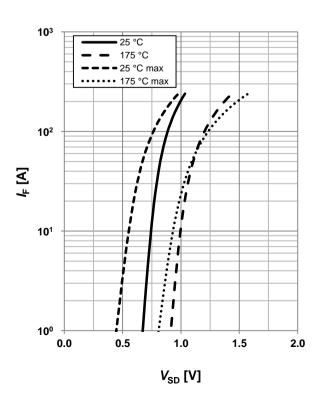
10 Typ. gate threshold voltage

 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ parameter: I_D



12 Forward characteristics of reverse diode

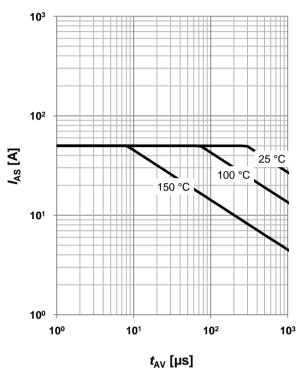
 $I_{\text{F}} = f(V_{\text{SD}})$ parameter: T_{i}





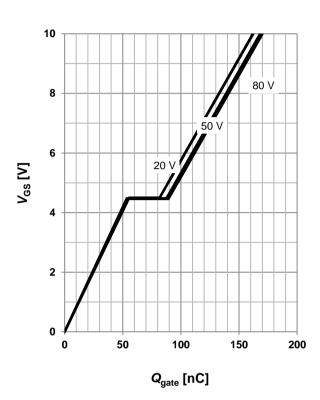
13 Avalanche characteristics

 $I_{\mathrm{AS}} = \mathrm{f}(t_{\mathrm{AV}}); \ R_{\mathrm{GS}} = 25 \ \Omega$ parameter: $T_{\mathrm{j(start)}}$



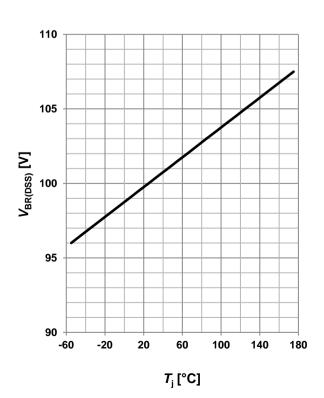
14 Typ. gate charge

 $V_{\rm GS} = f(Q_{\rm gate}); I_{\rm D} = 100$ A pulsed parameter: $V_{\rm DD}$



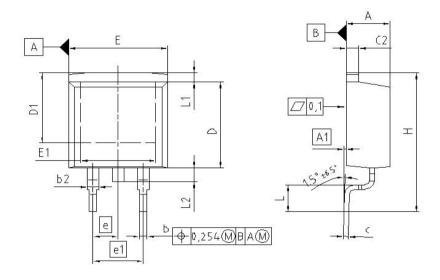
15 Drain-source breakdown voltage

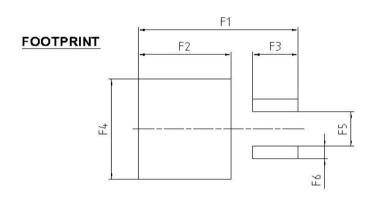
 $V_{BR(DSS)}=f(T_i); I_D=1 \text{ mA}$





PG-TO-263 (D²-Pak)





DIM	MILLIMETERS		INCHES			
DINI	MIN	MAX	MIN	MAX		
A	4.300	4.572	0.169	0.180		
A1	0.000	0.254	0.000	0.010		
b	0.650	0.850	0.026	0.033		
b2	0.950	1.321	0.037	0.052		
C	0.330	0.650	0.013	0.026		
с2	0.170	1.400	0.046	0.055		
D	8.509	9.450	0.335	0.372		
D1	7.100	-	0.280	-		
E	9.800	10.312	0.386	0.406		
E1	6.500		0.256			
e	2.5	2.540		0.100		
e1	5.0	5.080		0.200		
N	2	1	3	2		
Н	14.605	15.875	0.575	0.625		
L	2.200	3.000	0.087	0.118		
L1	-	1.600	-	0.063		
L2	1.000	1.778	0.039	0.070		
F1	16.050	16.250	0.632	0.640		
F2	9.300	9.500	0.366	0.374		
F3	4.500	4.700	0.177	0.185		
F4	10.700	10.900	0.421	0.429		
F5	3.630	3.830	0.143	0.151		
F6	1.100	1.300	0.043	0.051		

	REFERENCE JEDEC TO263		
SCALE	0-		
0	7.5mm		
EUROPEAN	PROJECTION		
-	-		
I SSUE 12-02			
	LE 263 2		



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